

Title (en)
SYSTEMS AND METHODS FOR DETERMINING THE QUALITY OF A REPRODUCED (MANUFACTURED) OPTIC DEVICE

Title (de)
SYSTEME UND VERFAHREN ZUR BESTIMMUNG DER QUALITÄT EINER REPRODUZIERTEN (GEFERTIGTEN) OPTISCHEN VORRICHTUNG

Title (fr)
SYSTÈMES ET PROCÉDÉS PERMETTANT DE DÉTERMINER LA QUALITÉ D'UN DISPOSITIF OPTIQUE (MANUFACTURÉ) REPRODUIT

Publication
EP 3218685 A4 20180704 (EN)

Application
EP 15858689 A 20151111

Priority

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Abstract (en)
[origin: WO2016074034A2] A method for assessing the similarity between a power profile of a manufactured optic device and a nominal power profile upon which the power profile of the manufactured optic device is based. The method comprises measuring the power profile of manufactured optic device, identifying a region of interest from the measured power profile of manufactured optic device, and applying an offset to the measured power profile to substantially minimize a statistical quantifier for quantifying the similarity between the nominal power profile and the offset measured power profile. The method further comprises comparing the offset and the statistical quantifier to predefined quality control metrics, determining whether the measured power profile meets the predefined quality control metrics based, at least in part on the comparison. In exemplary embodiments, the method may further comprise determining whether to associate the manufactured optic device with another nominal power profile, if the measured power profile does not meet the predefined quality control metrics.

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Citation (search report)

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- See references of WO 2016074034A2

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